

SN54LS137, SN74LS137 3-LINE TO 8-LINE DECODERS/DEMULTIPLEXERS WITH ADDRESS LATCHES

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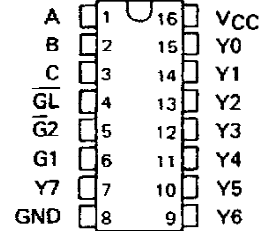
- Combines Decoder and 3-Bit Address Latch
- Incorporates 2 Enable Inputs to Simplify Cascading
- Low Power Dissipation . . . 65 mW Typ

description

The 'LS137 is a three-line to eight-line decoder/demultiplexer with latches on the three address inputs. When the latch-enable input (\overline{GL}) is low, the 'LS137 acts as a decoder/demultiplexer. When \overline{GL} goes from low to high, the address present at the select inputs (A, B, and C) is stored in the latches. Further address changes are ignored as long as \overline{GL} remains high. The output enable controls, G1 and $\overline{G2}$, control the state of the outputs independently of the select or latch-enable inputs. All of the outputs are high unless G1 is high and $\overline{G2}$ is low. The 'LS137 is ideally suited for implementing glitch free decoders in strobed (stored-address) applications in bus-oriented systems.

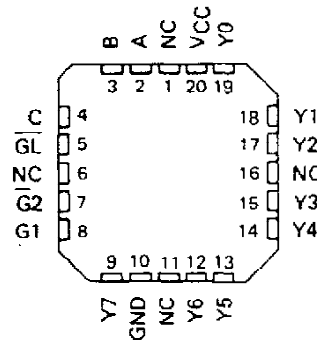
SN54LS137 . . . J OR W PACKAGE
SN74LS137 . . . D OR N PACKAGE

(TOP VIEW)



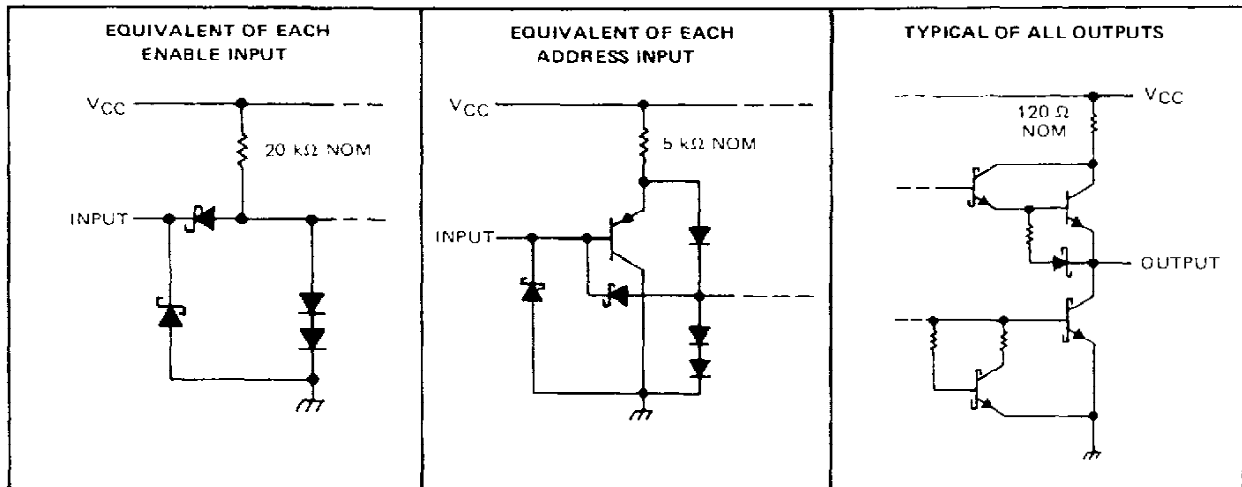
SN54LS137 . . . FK PACKAGE

(TOP VIEW)



NC - No internal connection

schematics of inputs and outputs



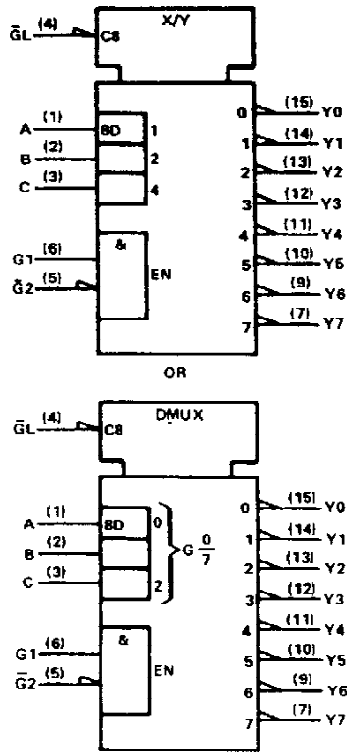
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SN54LS137, SN74LS137 3-LINE TO 8-LINE DECODERS/DEMULTIPLEXERS WITH ADDRESS LATCHES

logic symbols†



FUNCTION TABLE

INPUTS			OUTPUTS											
ENABLE		SELECT	C	B	A	Y0	Y1	Y2	Y3	Y4	Y5	Y6	Y7	
$\bar{G}1$	$\bar{G}2$		X	X	H	X	X	X	H	H	H	H	H	H
X	L	X	X	X	X	H	H	H	H	H	H	H	H	H
L	H	L	L	L	L	L	H	H	H	H	H	H	H	H
L	H	L	L	L	H	H	L	H	H	H	H	H	H	H
L	H	L	L	H	L	H	H	L	H	H	H	H	H	H
L	H	L	L	H	H	H	H	L	H	H	H	H	H	H
L	H	L	H	L	L	H	H	H	H	L	H	H	H	H
L	H	L	H	L	H	H	H	H	H	H	L	H	H	H
L	H	L	H	H	L	H	H	H	H	H	H	L	H	H
L	H	L	H	H	H	H	H	H	H	H	H	H	L	H
H	H	L	X	X	X	Output corresponding to stored address, L; all others, H								

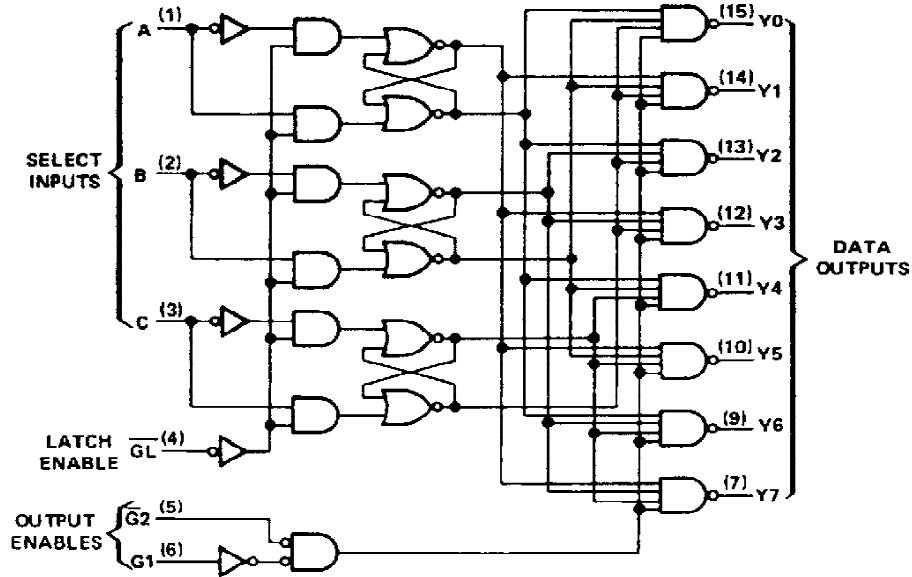
H = high level, L = low level, X = irrelevant

†These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

SN54LS137, SN74LS137 3-LINE TO 8-LINE DECODERS/DEMULTIPLEXERS WITH ADDRESS LATCHES

logic diagram (positive logic)



Pin numbers shown are for D, J, N, and W packages.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (See Note 1)	7 V
Input voltage	7 V
Operating free-air temperature range: SN54LS137	-55°C to 125°C
SN74LS137	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

SN54LS137, SN74LS137

3-LINE TO 8-LINE DECODERS/DEMULTIPLEXERS WITH ADDRESS LATCHES

recommended operating conditions

	SN54LS137			SN74LS137			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, V_{CC}	4.5	5	5.5	4.75	5	5.25	V
High-level output current, I_{OH}			-400			-400	μ A
Low-level output current, I_{OL}			4			8	mA
Width of enabling pulse at \overline{GL} , t_w	15			15			ns
Setup time at A, B, and C inputs, t_{SU}	10			10			ns
Hold time at A, B, and C inputs, t_H	10			10			ns
Operating free-air temperature, T_A	-55		125	0		70	$^{\circ}$ C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS [†]	SN54LS137			SN74LS137			UNIT
		MIN	TYP [‡]	MAX	MIN	TYP [‡]	MAX	
V_{IH} High-level input voltage		2			2			V
V_{IL} Low-level input voltage				0.7			0.8	V
V_{IK} Input clamp voltage	$V_{CC} = \text{MIN}$, $I_I = -18 \text{ mA}$			-1.5			-1.5	V
V_{OH} High-level output voltage	$V_{CC} = \text{MIN}$, $V_{IH} = 2 \text{ V}$, $V_{IL} = V_{IL \text{ max}}$, $I_{OH} = -400 \mu\text{A}$	2.5	3.5		2.7	3.5		V
V_{OL} Low-level output voltage	$V_{CC} = \text{MIN}$, $V_{IH} = 2 \text{ V}$, $V_{IL} = V_{IL \text{ max}}$							V
				$I_{OL} = 4 \text{ mA}$	0.25	0.4	0.25	0.4
				$I_{OL} = 8 \text{ mA}$			0.35	0.5
I_I Input current at maximum input voltage	$V_{CC} = \text{MAX}$, $V_I = 7 \text{ V}$			0.1			0.1	mA
I_{IH} High-level input current	$V_{CC} = \text{MAX}$, $V_I = 2.7 \text{ V}$			20			20	μ A
I_{IL} Low-level input current	$V_{CC} = \text{MAX}$, $V_I = 0.4 \text{ V}$							mA
				Enable	-0.4		-0.4	
				A, B, C	-0.2		-0.2	
I_{OS} Short-circuit output current [§]	$V_{CC} = \text{MAX}$	-20		-100	-20		-100	mA
I_{CC} Supply current	$V_{CC} = \text{MAX}$, See Note 2		11	18		11	18	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

[§] Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.

NOTE 2: I_{CC} is tested with all inputs grounded and all outputs open.

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$, see note 3

PARAMETER [†]	FROM (INPUT)	TO (OUTPUT)	LEVELS OF DELAY	TEST CONDITIONS	MIN	TYP	MAX	UNIT
^1PLH	A, B, C	Y	2	$C_L = 15 \text{ pF}$, $R_L = 2 \text{ k}\Omega$, See Note 3		11	17	ns
^1PHL			4			25	38	
^1PLH	A, B, C	Y	3			16	24	ns
^1PHL			3			19	29	
^1PLH	Enable $\overline{G}2$	Y	2			13	21	ns
^1PHL			2			16	27	
^1PLH	Enable G1	Y	3			14	21	ns
^1PHL			3			18	27	
^1PLH	Enable \overline{GL}	Y	3			18	27	ns
^1PHL			4			25	38	

[†] ^1PLH = propagation delay time, low-to-high-level output.

^1PHL = propagation delay time, high-to-low-level output.

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

TEXAS
INSTRUMENTS

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